


<b>Search Notes</b>  	<b>Application/Control No.</b>  10579542	<b>Applicant(s)/Patent Under Reexamination</b>  GUNTHER ET AL.
	<b>Examiner</b>  CHRIS C CHU	<b>Art Unit</b>  2815

SEARCHED			
Class	Subclass	Date	Examiner
257	E31.117, E33.068, 98 - 100, 431 - 434 and 680	12/6/09	C.C.
428	138	12/6/09	C.C.
257	E31.117, E33.068, 98 - 100, 431 - 434, 680, E31.118 and E31.13	3/3/10	C.C.
428	138	3/3/10	C.C.

SEARCH NOTES		
Search Notes	Date	Examiner
Searched in US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; and IBM_TDB;	12/6/09	C.C.
Searched in US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; and IBM_TDB;	3/3/10	C.C.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
As same as above	As same as above	3/3/10	C.C.

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